## Application/Control No. Applicant(s)/Patent Under Reexamination 10/779,842 KIM ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2871 James A. Dudek **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY US-2003/0025868 A1 02-2003 Hiroshima et al. 349/156 Α 349/156 В US-6,888,608 05-2005 Miyazaki et al. С US-US-D US-Ε F US-US-G US-Н 1 US-US-J US-K US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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